
Vacuum Breakdown at 110 GHz

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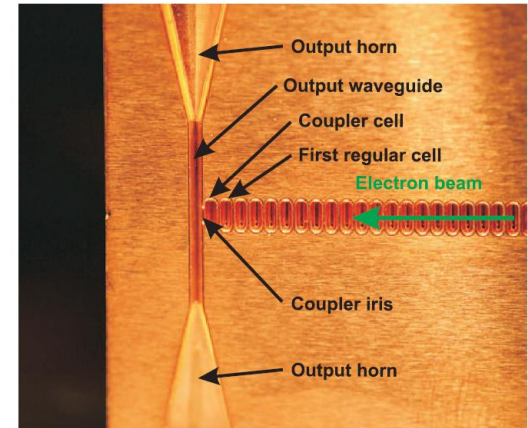
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Motivations and Goals

❑ Millimeter-wave RF LINAC structures have been the subject of recent research

- Wakefield structures tested by SLAC at FACET facility¹
- THz-driven electron LINAC demonstrated at MIT²



❑ There is a lack of experimental data on breakdown thresholds of materials at these frequencies (> 100 GHz)

- Due to historical lack of sources
- Megawatt gyrotrons have been developed for fusion applications

❑ Goals: Test breakdown thresholds of materials in physically simple geometries using a 110 GHz, 1.5 MW gyrotron

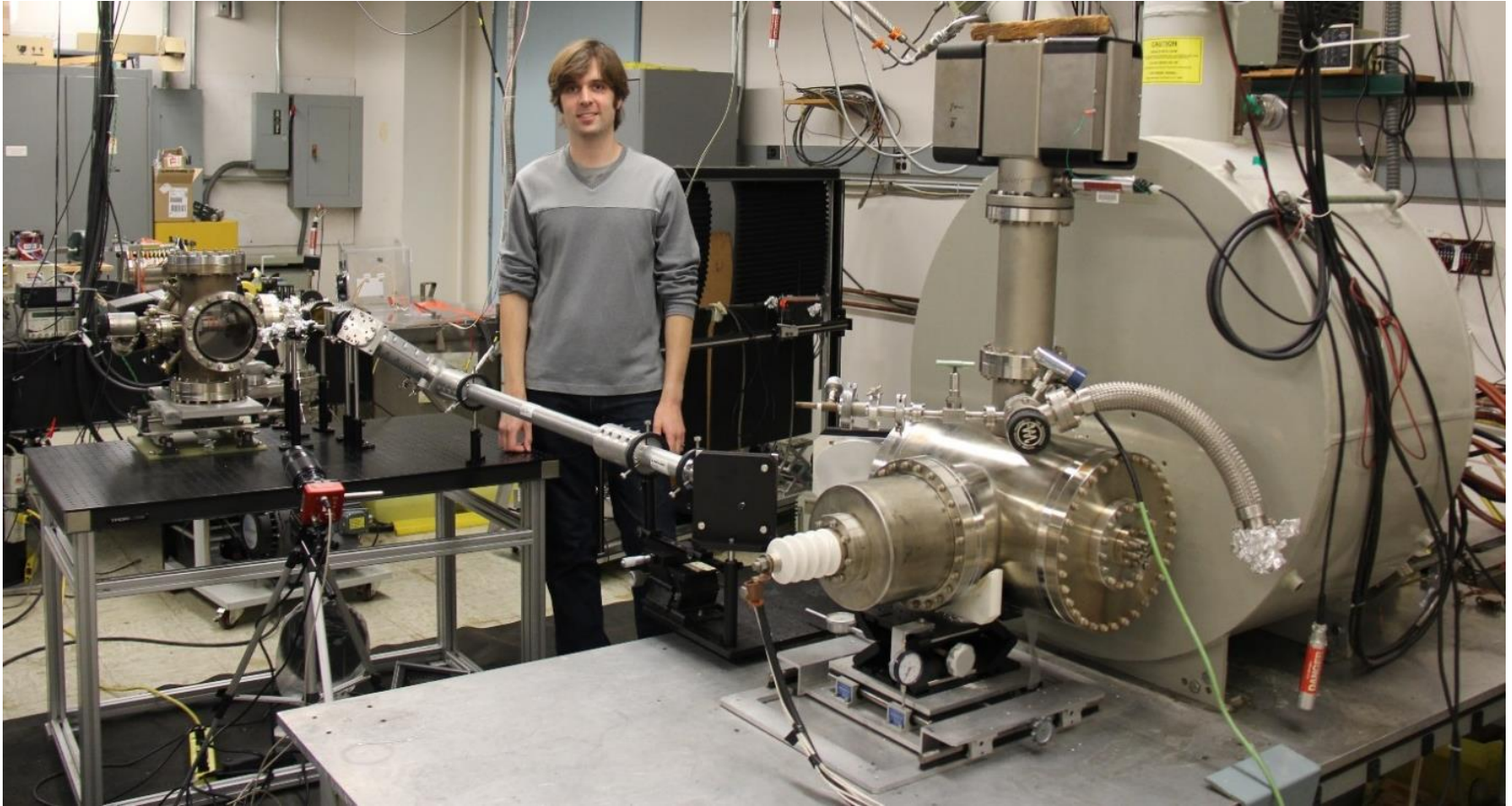
- Multipactor breakdown of dielectrics
- RF breakdown in simple metallic cavity in collaboration with SLAC³

1. M. Dal Forno et al., “Experimental measurements of rf breakdowns and deflecting gradients in mm-wave metallic accelerating structures,” Phys. Rev. Accel. Beams, vol. 19, p. 051302, (2016).

2. E. Nanni et al., “Terahertz-driven linear electron acceleration,” Nature Communications, vol. 6, p. 8486, (2016).

3. E. Nanni et al., “mm-Wave Standing-Wave Accelerating Structures for High-Gradient Tests” presented at IPAC16, Busan, Korea (2016)

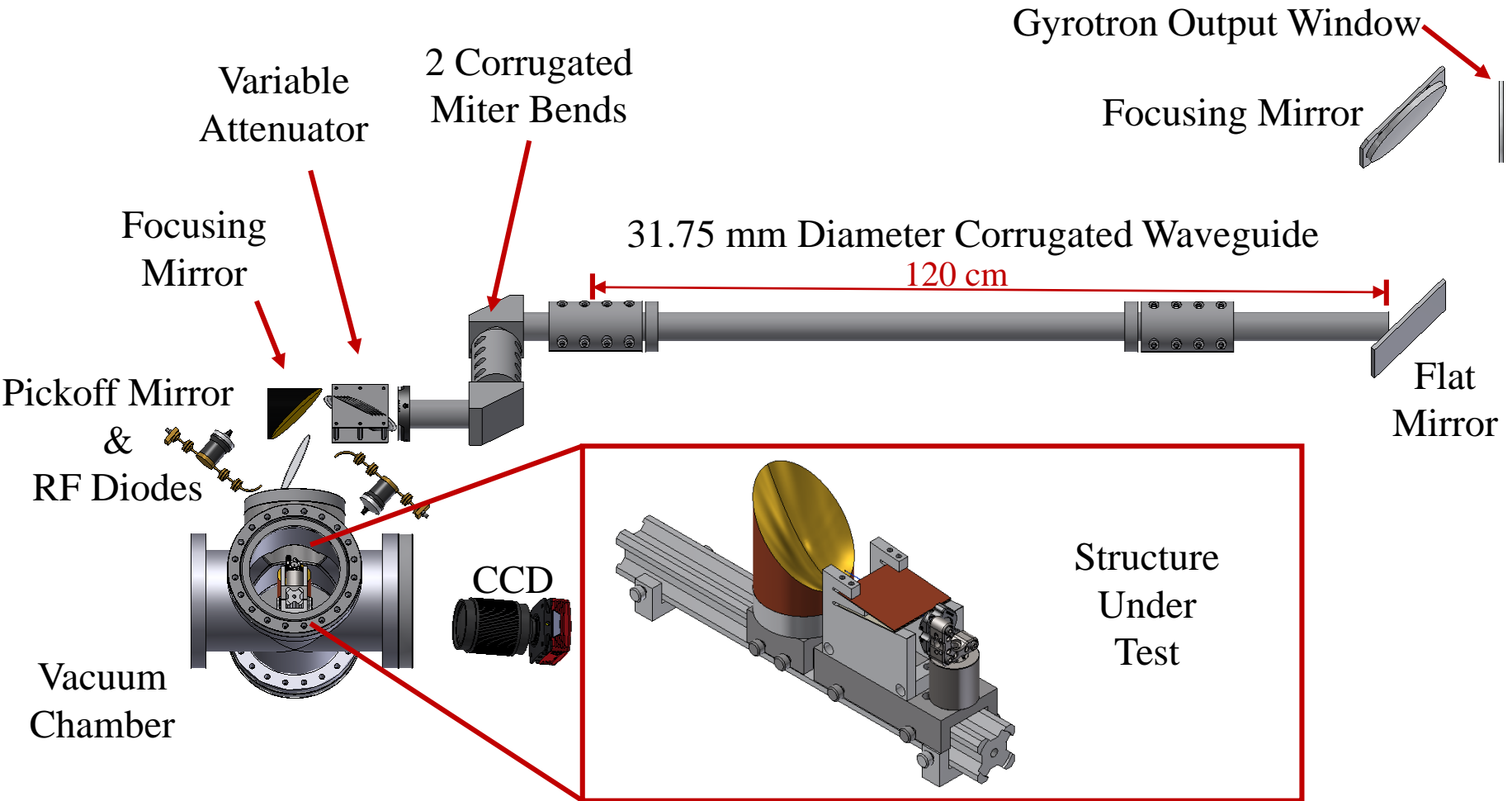
Experiment Overview



□ Gyrotron

- Up to 1.5 MW
- 110 GHz
- 3 μ s pulses
- 1 Hz rep. rate
- Gaussian beam output in free space

Experiment Overview

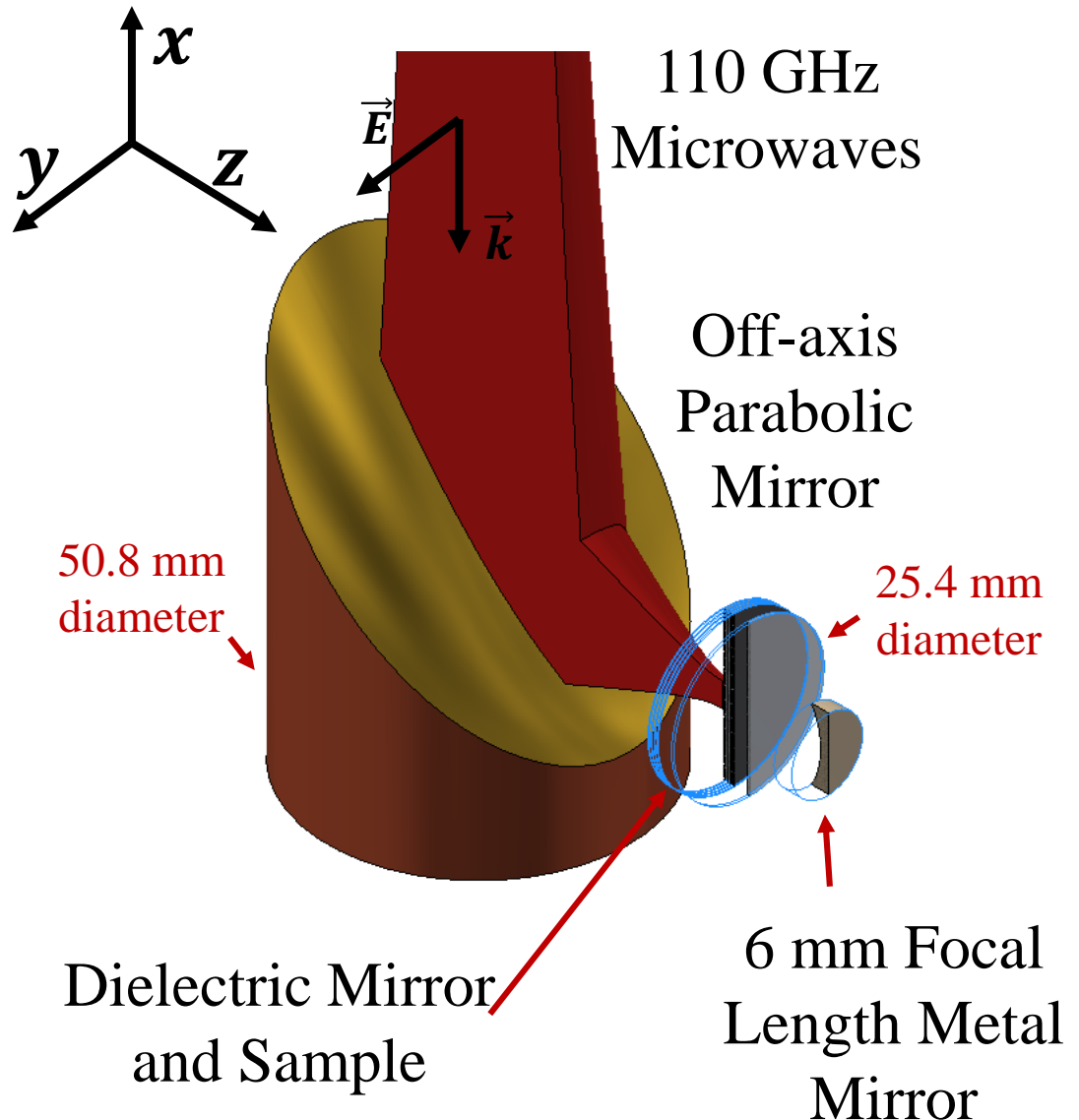


□ Diagnostics

- Forward and Reverse RF diode
- Visible light CCD imager
- Pressure Monitor

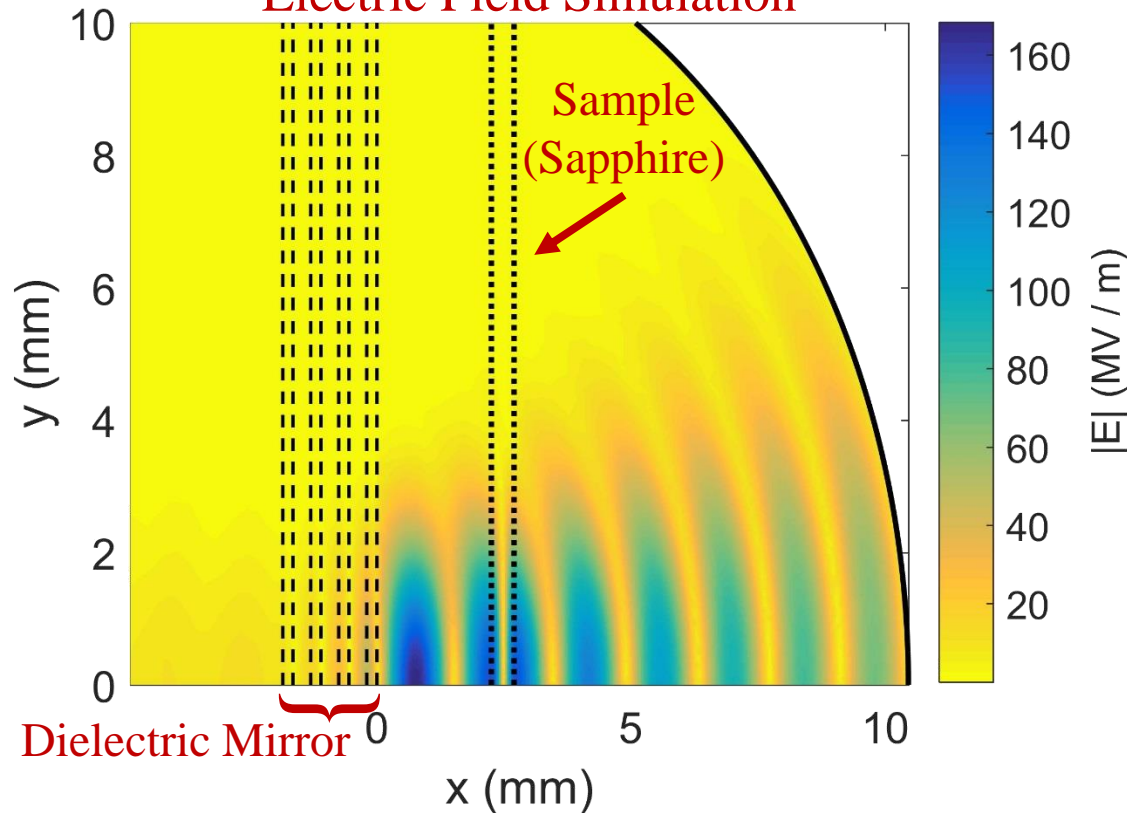
Parallel E-field Configuration

- ❑ Structure placed in vacuum chamber
- ❑ Fabry-Pérot cavity
 - Cavity formed between a layered dielectric mirror and a spherical mirror
 - Dielectric mirror
 - Alternating layers of polished HRFZ Si and fused quartz wafers
 - 25.4 mm diameter
- ❑ Gaussian microwave beam incident from $+x$
 - Linearly polarized in y
 - Focused to 2 mm spot size radius (0.7λ)

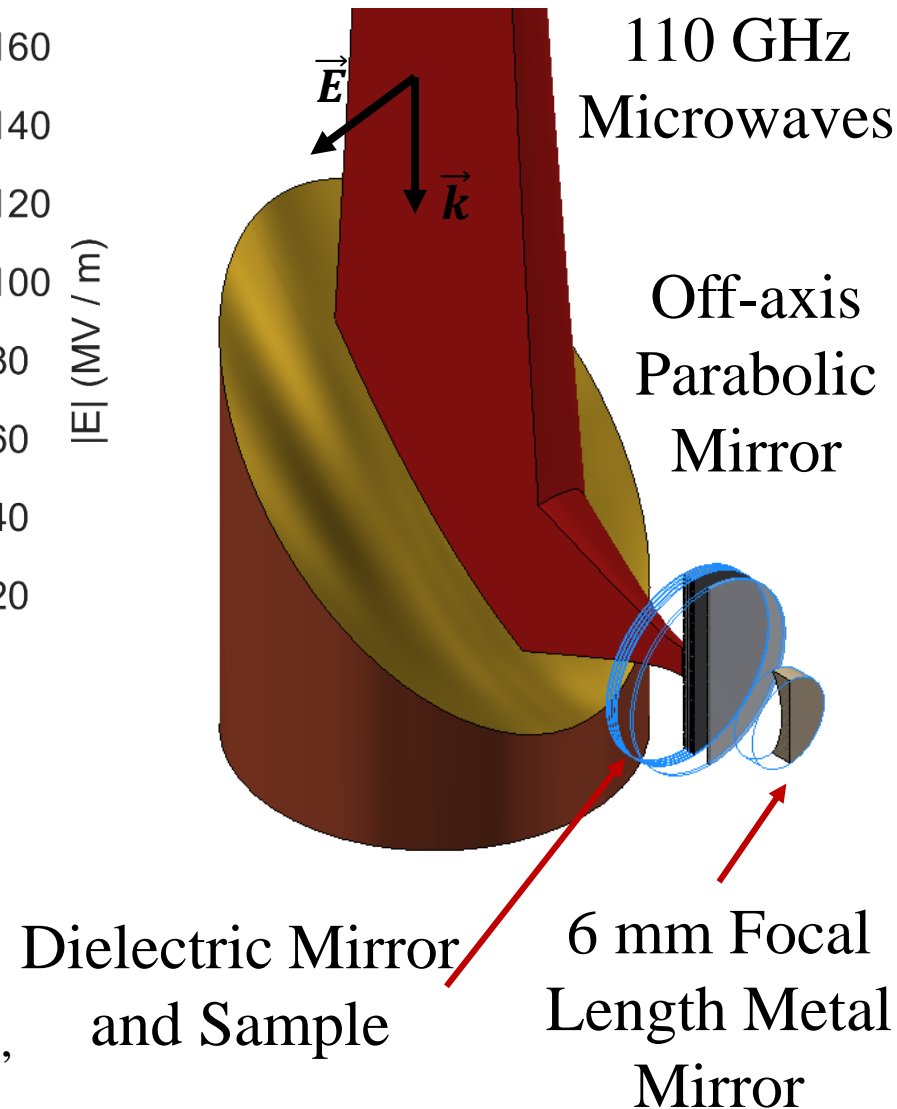


Parallel E-field Configuration

Electric Field Simulation

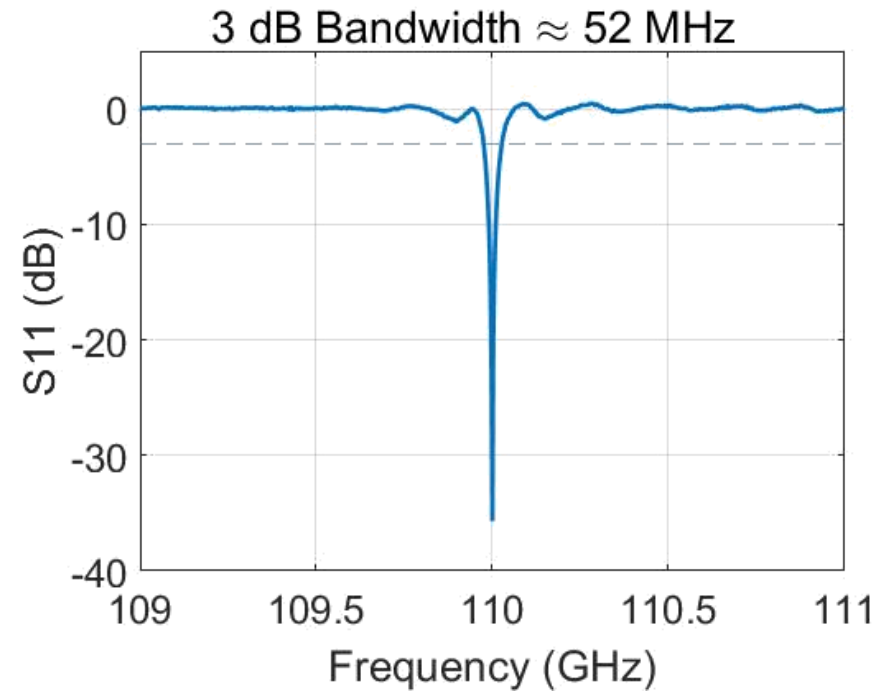
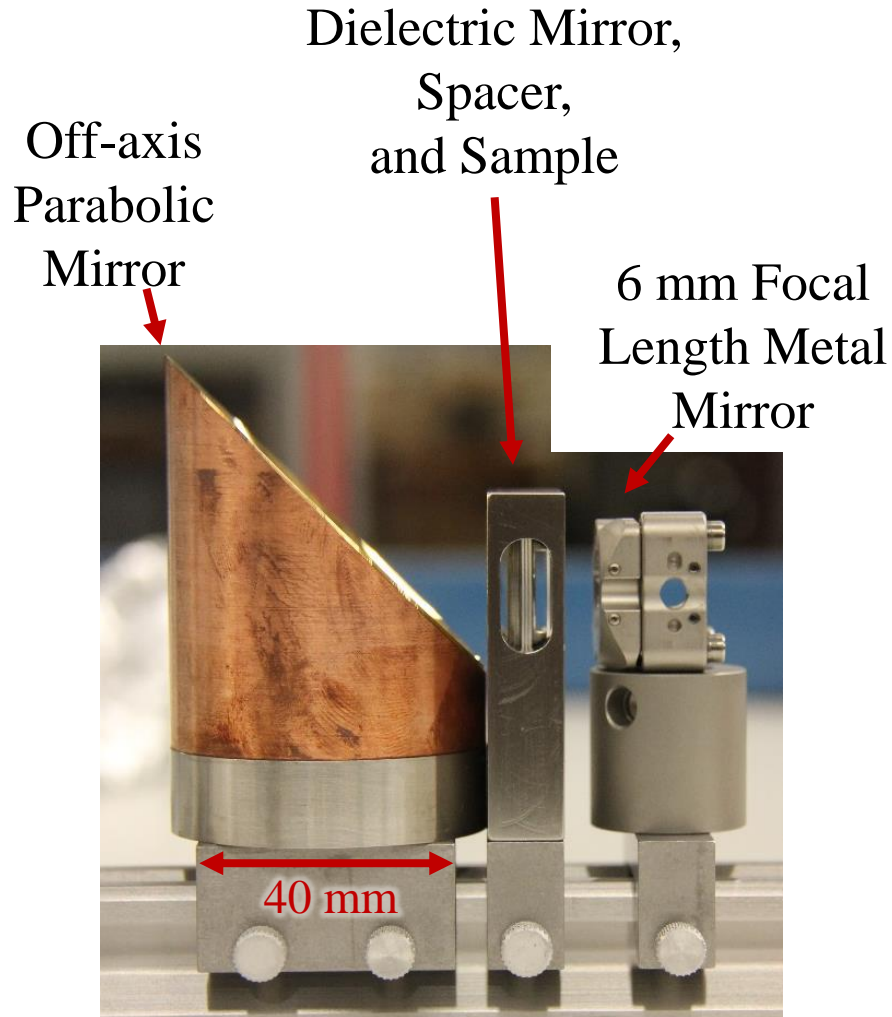


- ❑ 1 MW incident from right
- ❑ 150 MV/m on sample surface (< 30 MV/m on mirrors)
- ❑ Samples to be tested: crystal quartz, fused quartz, sapphire, 96% alumina, 99.9% alumina, HRFZ silicon



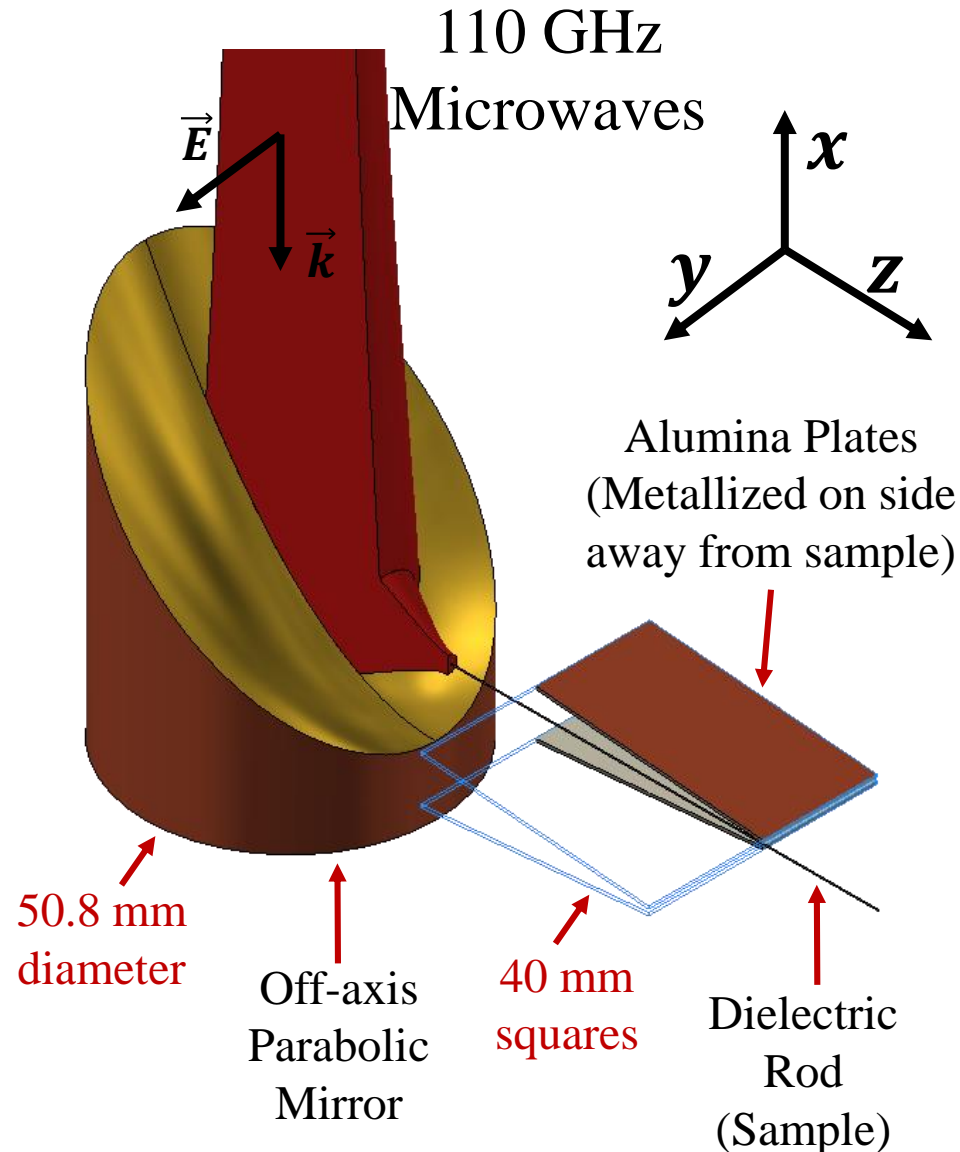
Parallel E-field Configuration

Low Power Test



Perpendicular E-Field Configuration

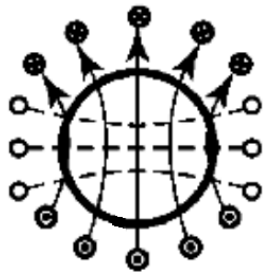
- Gaussian beam incident from + x direction
 - Linearly polarized in y direction
 - Focused to 1.5 mm spot size (0.55λ)
 - Focused on end of thin dielectric rod
- Sample is thin dielectric rod
 - 0.5 mm diameter for 99.8% alumina and sapphire
 - 0.8 mm diameter for fused quartz
- ~90% coupling to single propagating mode of dielectric rod waveguide
- Mode squeezed between two polished 99.9% alumina plates
 - Plates metalized with silver on sides away from sample



Perpendicular E-Field Configuration

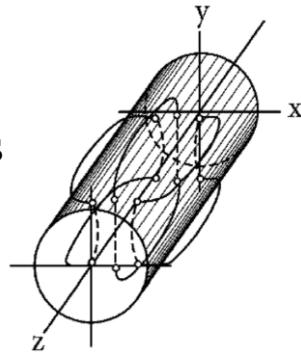
□ HE_{11} mode on a dielectric rod:

- E-field concentrated on two sides

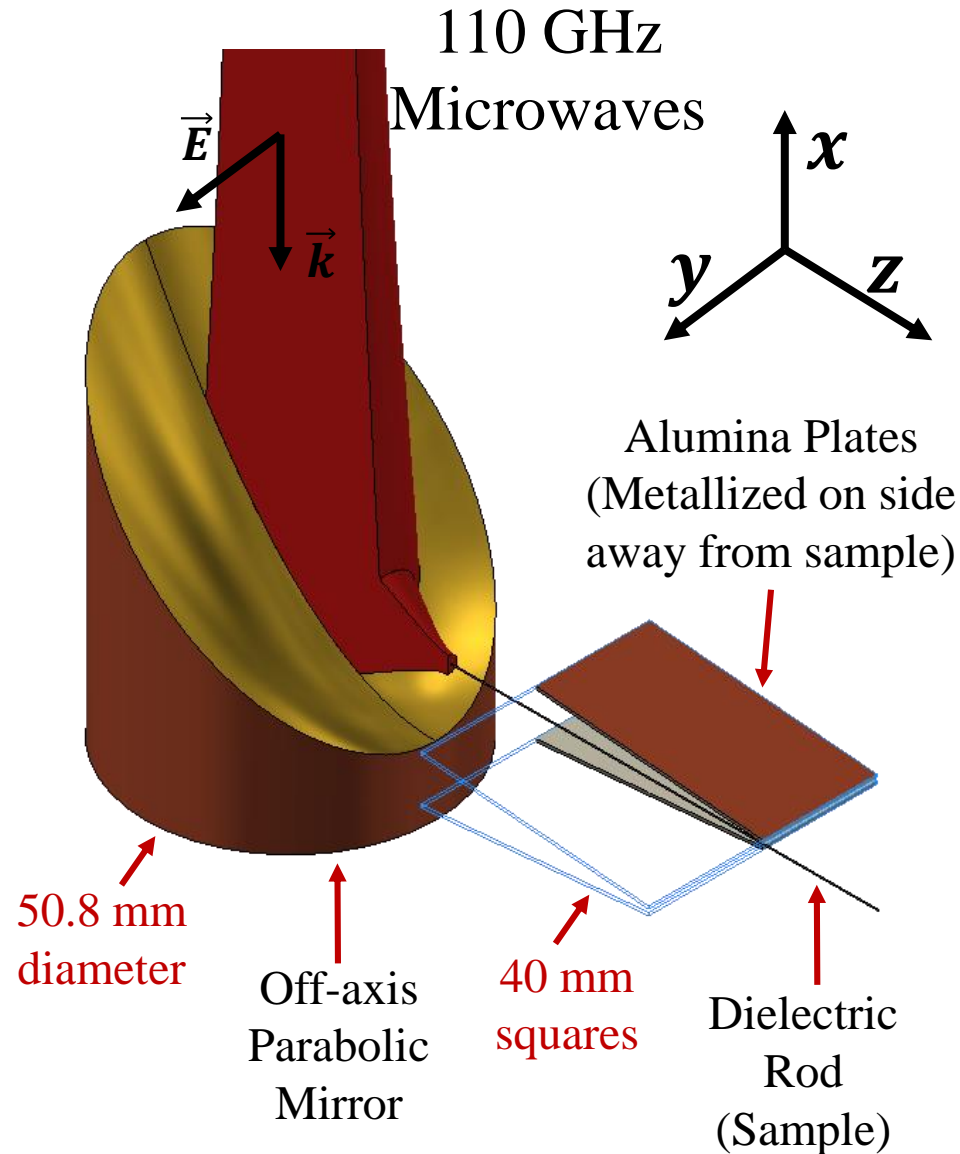
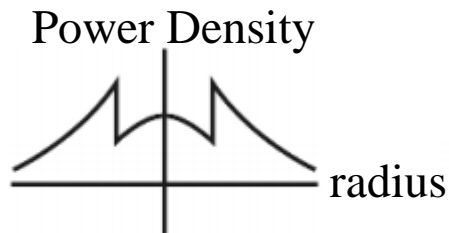


Solid: E-field
Dashed: H-field

- E-field lines form loops along rod



- Power density concentrated along surface of thin rods



Perpendicular E-Field Configuration

- ❑ Gaussian beam incident from left

- 1 MW of power

- ❑ Fields polarized in y

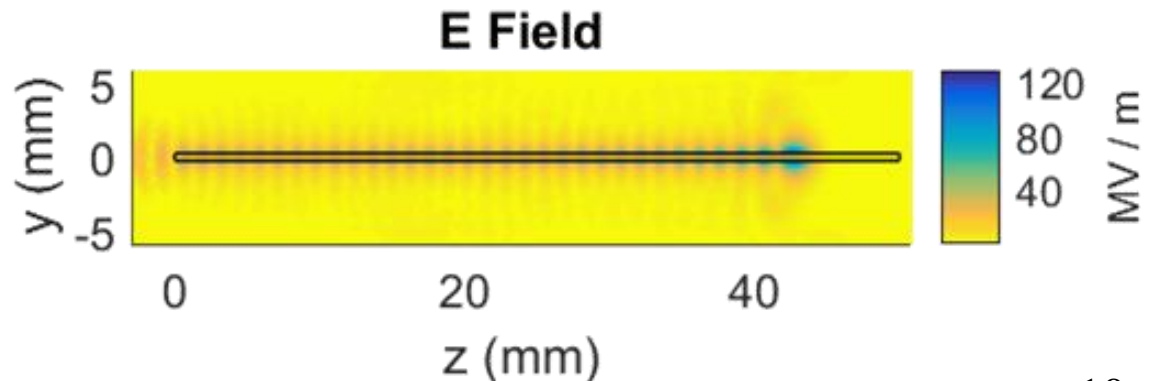
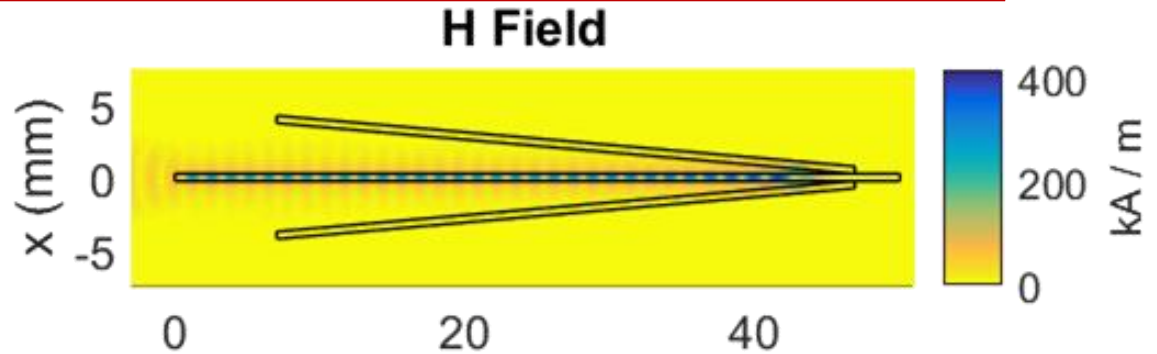
- Strong E-fields on sides of rod (away from alumina plates)

- ❑ Alumina plates squeeze magnetic field of dielectric rod waveguide mode

- Plates are metalized on sides away from the rod
- Cutoff mode near end of plates
- Creates standing wave on rod

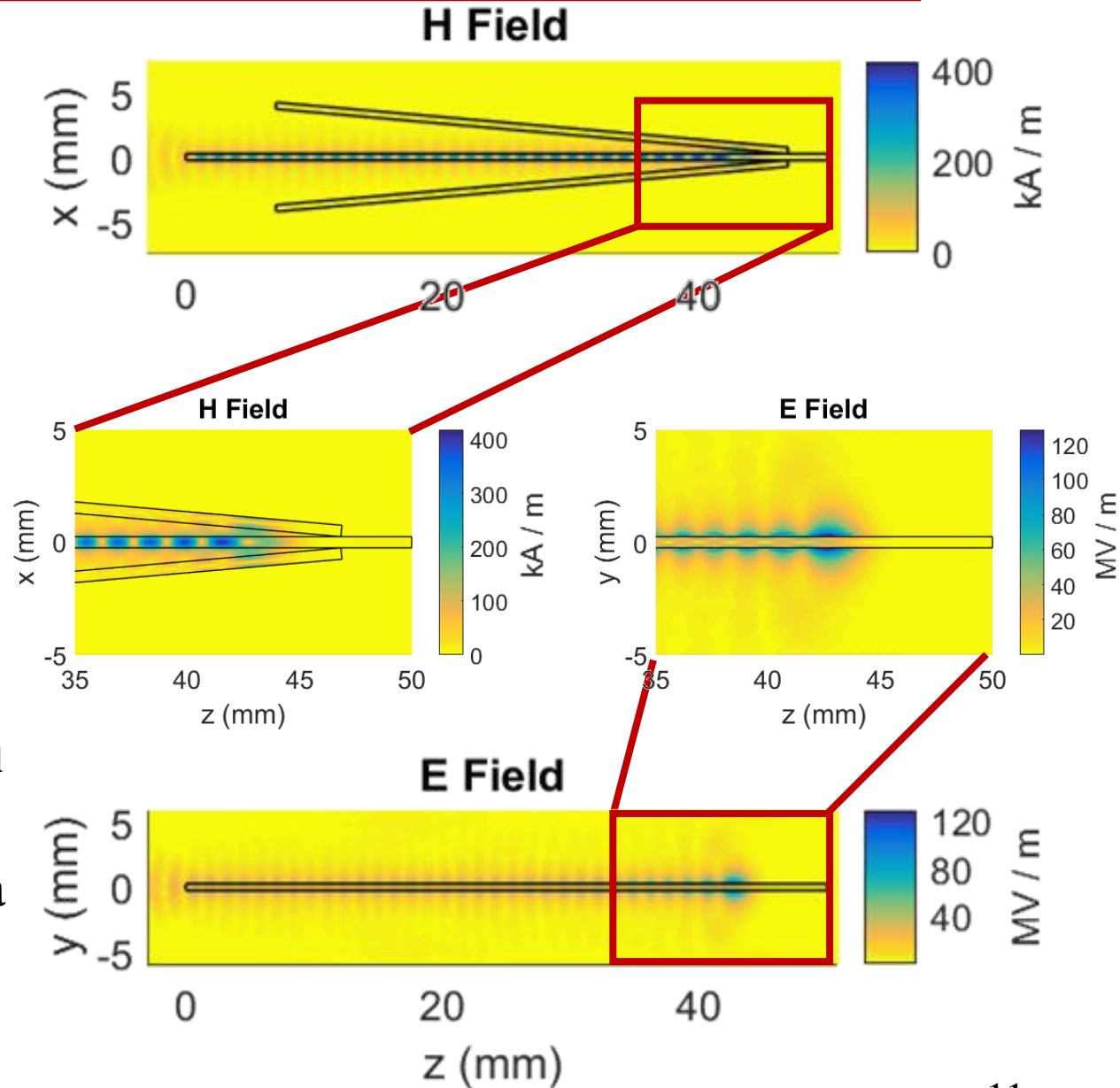
- ❑ Max field on surface of sapphire and alumina rods:

125 MV/m (lower for fused quartz)



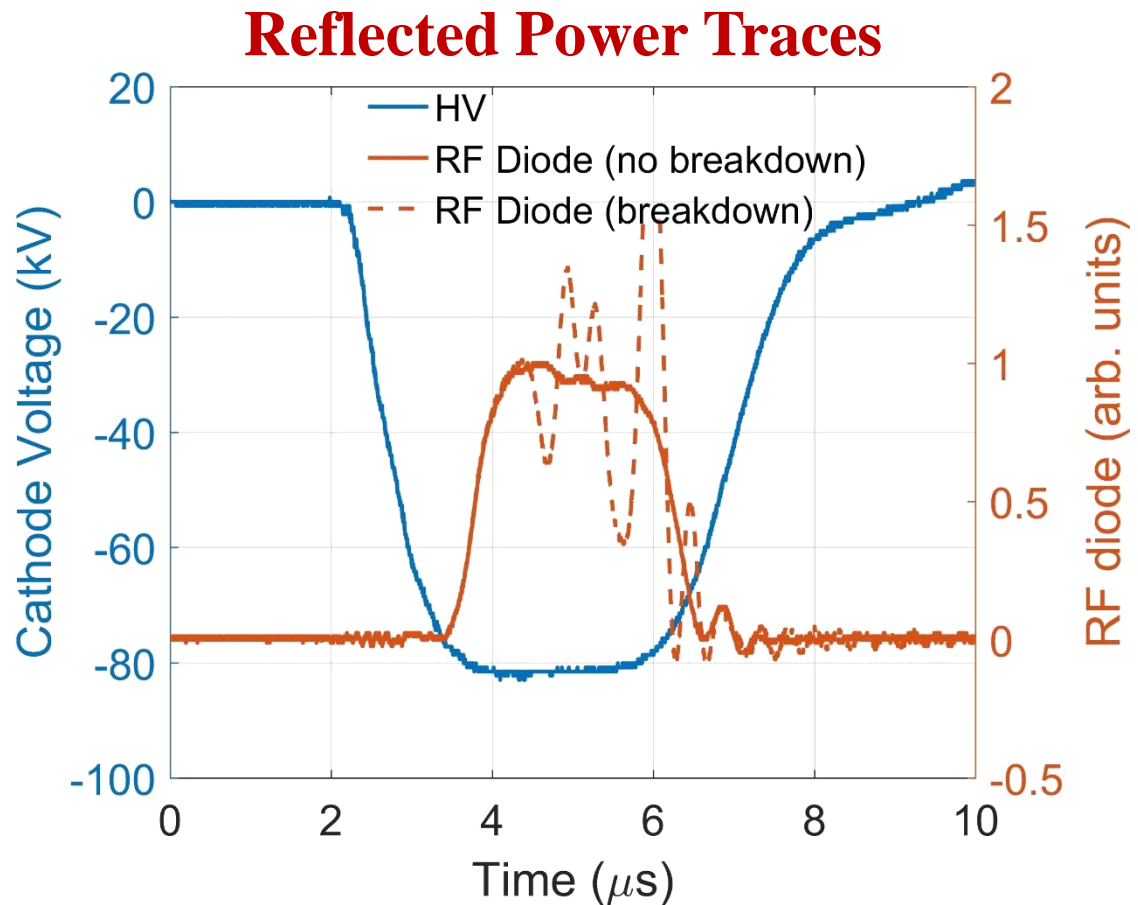
Perpendicular E-Field Configuration

- ❑ Gaussian beam incident from left
 - 1 MW of power
- ❑ Fields polarized in y
 - Strong E-fields on sides of rod (away from alumina plates)
- ❑ Alumina plates squeeze magnetic field of dielectric rod waveguide mode
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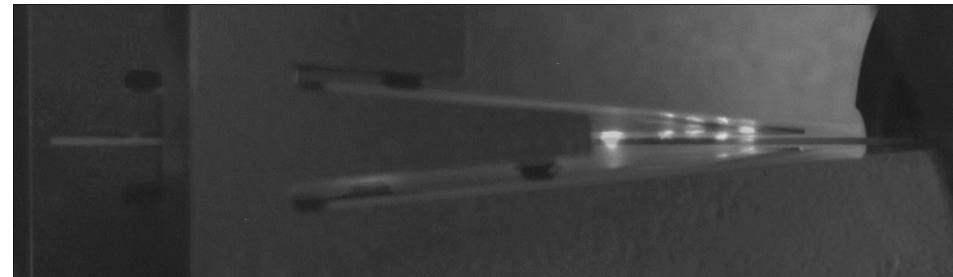
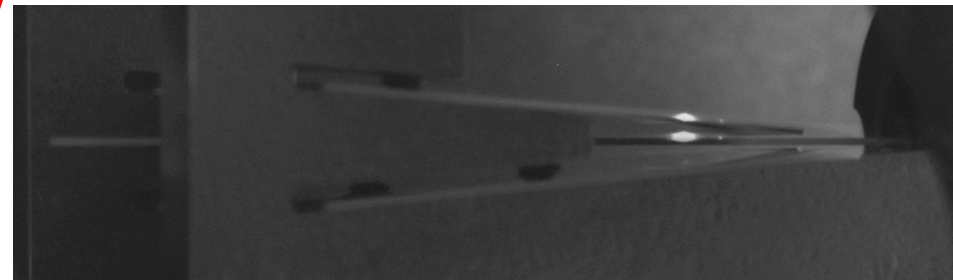
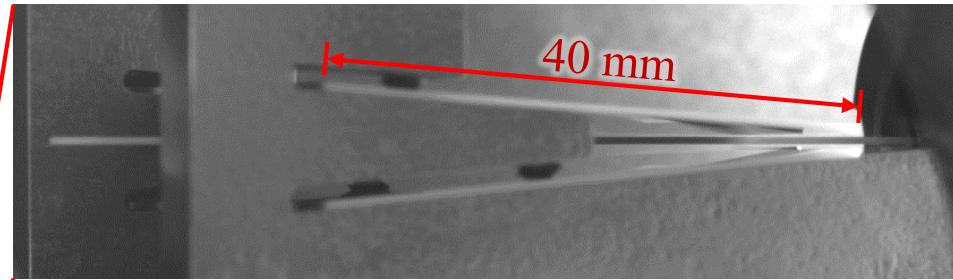
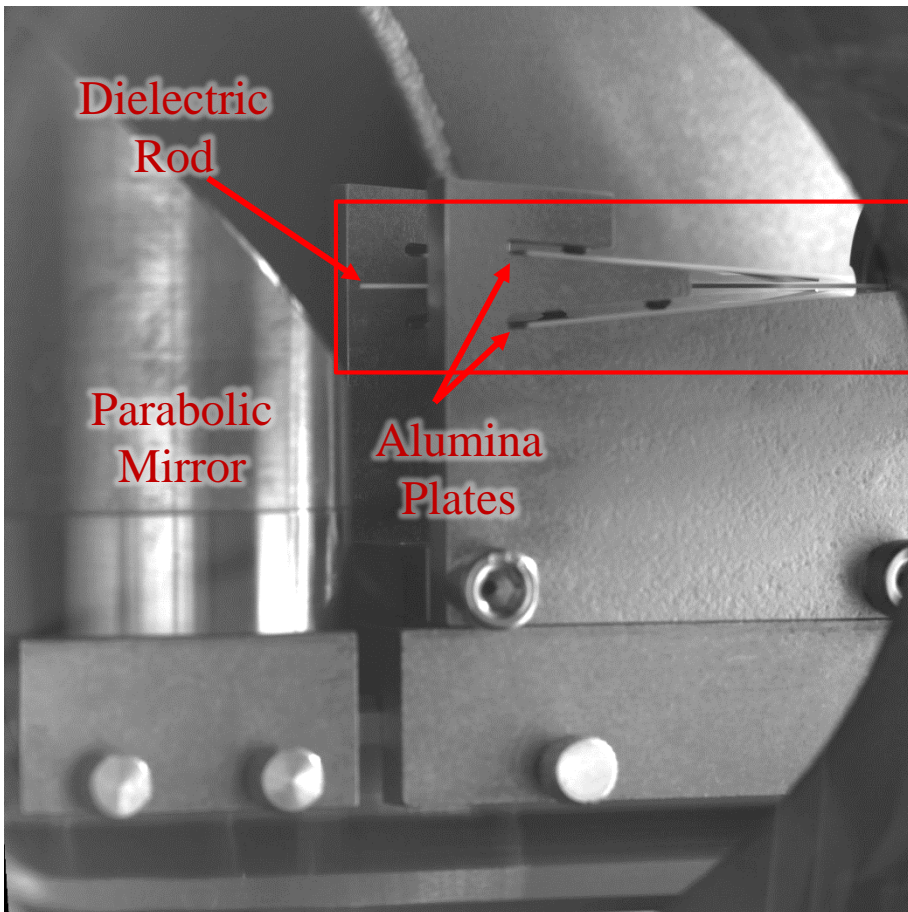


High Power Testing (Perp E-field)

- ❑ High power testing has begun on the dielectric rod (perpendicular E-field) configuration
- ❑ Base vacuum pressure
 - 1×10^{-8} Torr
- ❑ Breakdown detection
 - Pressure rises to a few $\times 10^{-7}$ Torr
- ❑ Breakdown visible on reverse power RF diode trace



High Power Testing (Perp E-field)



- ☐ Visible light images capture breakdowns
- ☐ Breakdowns occur reproducibly at the same locations along the rod

High Power Testing (Perp E-field)

- ❑ First tests on 99.8% alumina rod
- ❑ Currently tested up to 25 MV/m fields
 - Breakdowns from outgassing as power is ramped up
 - Breakdown rate at a given power drops to zero after < 100 shots
 - Threshold for multipactor breakdown not yet reached
- ❑ Testing is ongoing
- ❑ Current result: for 99.8% alumina with E-fields perpendicular to the surface, multipactor breakdown threshold > 25 MV/m



Future Work

- ❑ Continue high power tests on dielectric rods (Perpendicular E-field)
- ❑ Begin high power tests on dielectric windows (Parallel E-field)
- ❑ Install additional diagnostics
 - Photodiode
 - Spectroscopy
 - Dark current probe
 - ICCD imager (2 ns exposures)
- ❑ Test RF breakdown threshold in metallic cavity in collaboration with SLAC
 - S. Tantawi group
 - Gaussian beam to TM_{01} mode converter and TM_{01} cavity designed by SLAC
 - Will require shortening gyrotron pulse from 3 μ s to ns timescale

Summary

- ❑ Experiments have been designed to test multipactor breakdown thresholds of dielectrics
 - Two designs for testing fields either parallel to or perpendicular to the sample surface
 - Testing with high power, 110 GHz has begun
 - Materials to be tested
 - Parallel E-field: crystal quartz, fused quartz, 96% and 99.9% alumina, sapphire, HRFZ Silicon
 - Perpendicular E-field: fused quartz, 99.8% alumina, sapphire
 - Currently functioning diagnostics
 - Forward and reverse power RF diodes, pressure monitor, visible light CCD imager
 - Additional diagnostics will be added
 - Photodiode for time resolution
 - Dark current probe
- ❑ More high power testing to be done
- ❑ Future testing of metallic structures will be done in collaboration with SLAC



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